TOSHIBA Field Effect Transistor Silicon N Channel MOS Type(MACH II π -MOSIV)

TK13H90A1

Swiching Regulator Applications

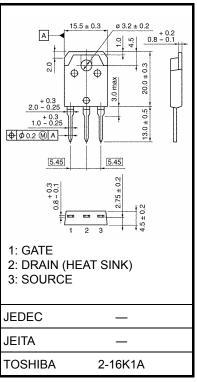
Unit: mm

•	Low drain-source ON res	istance	$: R_{DS} (ON) = 0.78\Omega (typ.)$
•	High forward transfer adr	nittance	$ Y_{fs} = 11S \text{ (typ.)}$
•	Low leakage current	$: I_{DSS} = 1$	$100 \mu\text{A} (\text{max}) (\text{V}_{\text{DS}} = 720\text{V})$

• Enhancement mode : $V_{th} = 2.0 \sim 4.0 \text{ V (V}_{DS} = 10 \text{ V, I}_{D} = 1 \text{ mA})$

Absolute Maximum Ratings (Ta = 25°C)

Characteris	stics	Symbol	Rating	Unit	
Drain-source voltage		V_{DSS}	900	V	
Drain-gate voltage (Ro	_{SS} = 20 kΩ)	V_{DGR}	900	V	
Gate-source voltage		V _{GSS}	±30	V	
Drain current	DC (Note 1)	I _D	13	Α	
Dialii Cuitent	Pulse (Note 1)	I _{DP}	39	Α	
Drain power dissipation	n (Tc = 25°C)	P _D	150	W	
Single pulse avalanche	e energy (Note 2)	E _{AS}	491	mJ	
Avalanche current		I _{AR}	13	Α	
Repetitive avalanche energy (Note 3)		E _{AR}	15	mJ	
Channel temperature		T _{ch}	150	°C	
Storage temperature ra	ange	T _{stg}	-55~150	°C	



Weight: 3.8 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Thermal Characteristics

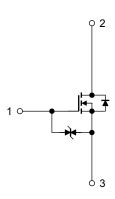
Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R _{th (ch-c)}	0.833	°C/W
Thermal resistance, channel to ambient	R _{th (ch-a)}	50	°C/W

Note 1: Ensure that the channel temperature does not exceed 150°C.

Note 2: V_{DD} = 90 V, T_{ch} = 25°C (initial), L = 5.3 mH, R_G = 25 Ω , I_{AR} = 13 A

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device. Please handle with caution.



Electrical Characteristics (Ta = 25°C)

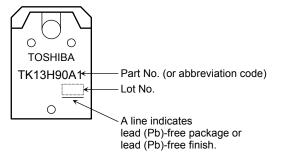
Charac	Characteristics Symbol Test Condition		Min	Тур.	Max	Unit	
Gate leakage current		I _{GSS}	V _{GS} = ±30 V, V _{DS} = 0 V	_	_	±10	μA
Gate-source bre	eakdown voltage	V (BR) GSS	I _G = ±10 μA, V _{DS} = 0 V	±30	_	_	V
Drain cut-off cu	rrent	I _{DSS}	V _{DS} = 720 V, V _{GS} = 0 V	_	_	100	μA
Drain-source br	eakdown voltage	V (BR) DSS	I _D = 10 mA, V _{GS} = 0 V	900	_	_	V
Gate threshold v	oltage	V _{th}	V _{DS} = 10 V, I _D = 1 mA	2.0	_	4.0	V
Drain-source O	N resistance	R _{DS} (ON)	V _{GS} = 10 V, I _D = 6.5 A	_	0.78	0.95	Ω
Forward transfer	admittance	Y _{fs}	V _{DS} = 10 V, I _D = 6.5 A	5.0	11	_	S
Input capacitano	:e	C _{iss}		_	2790	_	
Reverse transfer capacitance		C _{rss}	V _{DS} = 25 V, V _{GS} = 0 V, f = 1 MHz	_	25	_	pF
Output capacitance		Coss		_	300	_	
	Rise time	t _r	$V_{GS} = \frac{10V}{0V} = \frac{I_D=6.5}{V_{Out}} $ $V_{GS} = \frac{10V}{0V} = \frac{1}{10} = \frac{6.5}{V_{Out}} $ $V_{DD}=400V$ $V_{DD}=400V$ $V_{DD}=400V$	_	53	_	
Cuitabina tima	Turn-on time	t _{on}		_	88	_	
Switching time	Fall time	t _f		_	43	_	ns
	Turn-off time	t _{off}		_	165	_	
Total gate charge (gate-source plus gate-drain)		Qg		_	45		
Gate-source charge		Q _{gs}	$V_{DD} \approx 400 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 13 \text{ A}$		32	_	nC
Gate-drain ("miller") Charge		Q _{gd}			13	_	

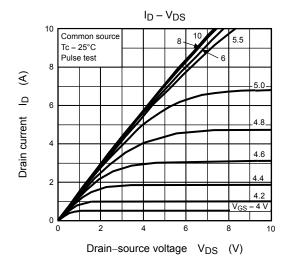
Source-Drain Ratings and Characteristics (Ta = 25°C)

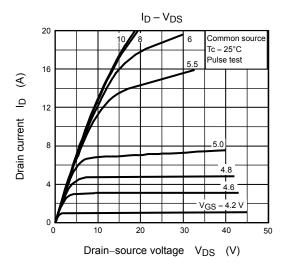
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I _{DR}	_	_	_	13	Α
Pulse drain reverse current (Note 1)	I _{DRP}	_	_	_	39	Α
Forward voltage (diode)	V _{DSF}	I _{DR} = 13 A, V _{GS} = 0 V	_	_	-1.7	V
Reverse recovery time	t _{rr}	I _{DR} = 13 A, V _{GS} = 0 V		1400	_	ns
Reverse recovery charge	Q _{rr}	Q_{rr} dI_{DR} / $dt = 100 A / \mu s$		24	_	μC

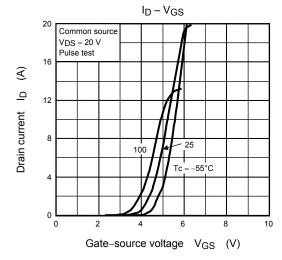
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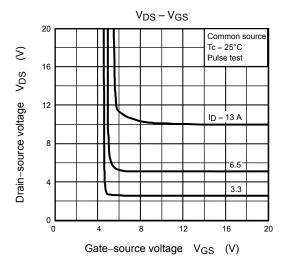
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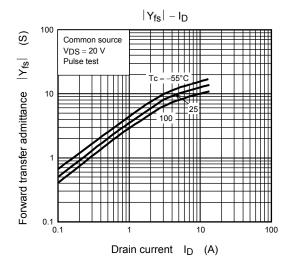


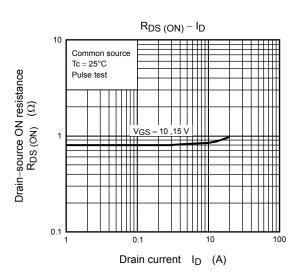


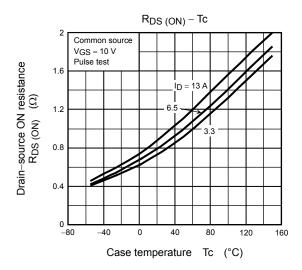


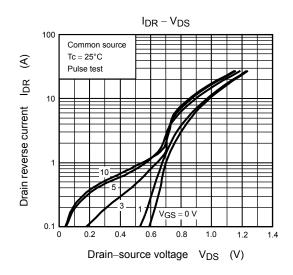


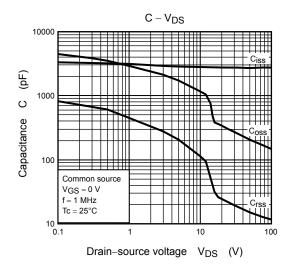


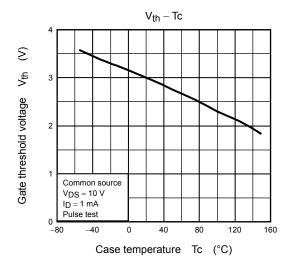


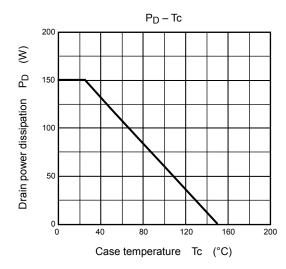


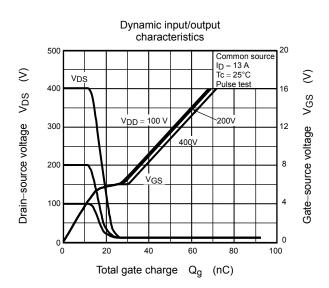


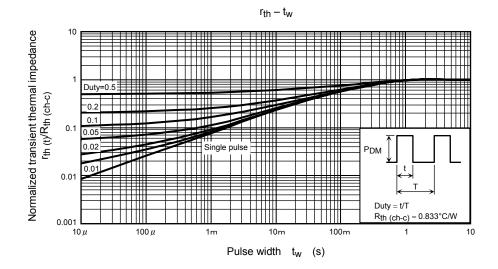


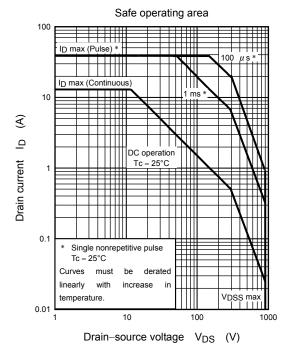


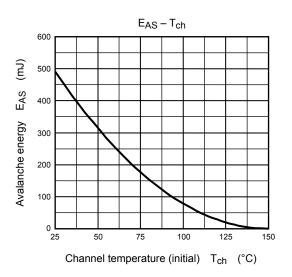


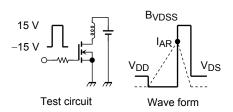












$$\begin{aligned} &R_G = 25~\Omega \\ &V_{DD} = 90~V,~L = 5.3~mH \end{aligned} \qquad EAS = \frac{1}{2} \cdot L \cdot I^2 \cdot \left(\frac{BVDSS}{BVDSS - V_{DD}} \right)$$

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